

**INFORMATION DISCLOSURE CITATION**

<b>Attorney's Docket No.</b>  <b>HAMM</b>	<b>Applicant</b>  <b>Siemens Aktiengesellschaft</b>	<b>Appl. No.</b>  <b>10/619,759</b>
<b>Filing Date</b>  <b>July 14, 2003</b>	<b>Group</b>  <b>2128</b>	<b>Examiner</b>  <b>Ferris, III, Fred O</b>

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date, if appropriate

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date	Country	Class	Subclass	Translation
	11120216 A	04-30-1999	Japan			

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

		Martin Otter: "Objektorientierte Modellierung physikalischer Systeme", in: at-Automatisierungstechnik, Vol. 48, No. 12, p. A65-A68, 2000
		Olaf Moseler & Rolf Isermann: "Fehlerfrüherrkennung", in: atp-Automayisierungs-technikpraxis, Vol. 42, No. 8, p. 29-36, 2000
		Bernhard Beetz: "Rechnermodell fur frühen Prüfung von Steuergeräten", in: atp, Vol. 42, No. 8, pa. 15, 2000

**Examiner:****Date considered:**

\*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.